

Data sheet acquired from Harris Semiconductor SCHS038C – Revised October 2003

CMOS 4-Stage Parallel In/Parallel Out Shift Register

with J-K Serial Inputs and True/Complement Outputs

High-Voltage Types (20-Volt Rating)

■ CD4035B is a four-stage clocked signal serial register with provision for synchronous PARALLEL inputs to each stage and SERIAL inputs to the first stage via JK logic. Register stages 2, 3, and 4 are coupled in a serial D flip-flop configuration when the register is in the serial mode (PARALLEL/SERIAL control low).

Parallel entry into each register stage is permitted when the PARALLEL/SERIAL control is high.

In the parallel or serial mode information is transferred on positive clock transitions.

When the TRUE/COMPLEMENT control is high, the true contents of the register are available at the output terminals. When the TRUE/COMPLEMENT control is low, the outputs are the complements of the data in the register. The TRUE/COMPLEMENT control functions asynchronously with respect to the CLOCK-signal.

JK input logic is provided on the first stage SERIAL input to minimize logic requirements particularly in counting and sequence-generation applications. With JK inputs connected together, the first stage becomes a D flip-flop. An asynchronous common RESET is also provided.

The CD4035B types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

Features:

- 4-Stage clocked shift operation
- Synchronous parallel entry on all 4 stages
- JK inputs on first stage
- Asynchronous True/Complement control on all outputs
- Static flip-flop operation; Master-slave configuration
- Buffered inputs and outputs
- High speed 12 MHz (typ.) at V_{DD} = 10 V
- 100% tested for quiescent current at 20 V
- Standardized, symmetrical output characteristics
- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of "B" Series CMOS Devices"

Applications:

- Counters, Registers
 Arithmetic-unit registers
 Shift-left shift right registers
 Serial-to-parallel/parallel-to-serial conversions
- Sequence generation
- Control circuits
- Code conversion

FIRST STAGE TRUTH TABLE

	†n-	(INP	JTS }	tn (OUTPUTS)	
CL	J	K	R	Q _{n-1}	Qn
	0	х	0	0	0
	1	х	0	0	ı
	х	0	0	ı	0
	1	0	0	Q _{n-1}	Q _{n-1} TOGGLE MODE
	х	-	0	1	ı
	x	x	0	Q _{n-1}	Q _{n-I}
×	х	х	ı	×	0

PARALLEL IN 9 1 10 2 11 3 12 4 SER. 5 4 CLK 6 P/S 7 T/C 2 RESET 5 VOD *16 VSS *8 Q1/Q1 Q2/Q2 Q3/Q3 Q4/Q4 T/C' OUT 92C9 - 29054R1 FUNCTIONAL DIAGRAM

CD4035B Types

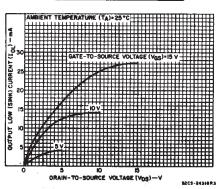


Fig. 1 — Typical output low (sink) current characteristics.

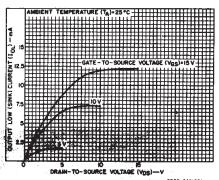
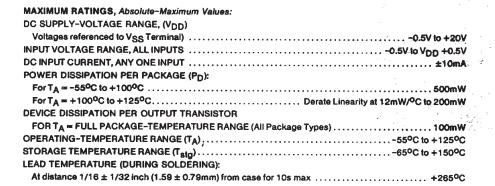


Fig. 2 - Minimum output low (sink)

current characteristics.

Fig. 3 — Typical output high (source) current characteristics.



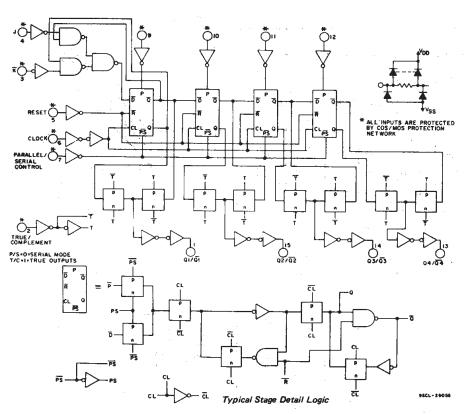


Fig. 4 - Logic diagram.

RECOMMENDED OPERATING CONDITIONS at $T_A = 25^{\circ}$ C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V_{DD}	LII	UNITS	
	 (V)	MIN.	MAX.	
Supply-Voltage Range (For T _A = Full Package-Temperature Range)		3	18	V
Data Setup Time, t _S : J/K Lines	5 10 15	220 80 60	- -	ns
Parallel-In Lines	5 10 15	140 50 40	-	ns
Clock Pulse Width, t _W	5 10 15	200 90 60	_ 	ns
Clock Input Frequency, fCL	5 10 15	dc	2 6 8	MHz
Clock Rise or Fall Time, t _r CL, t _f CL:	5 10 15		15 15 15	μs
Reset Pulse Width, t _W	5 10 15	250 110 80		ns

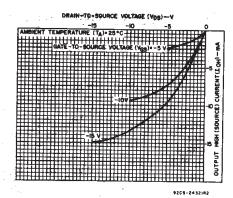


Fig. 5 — Minimum output high (source) current characteristics.

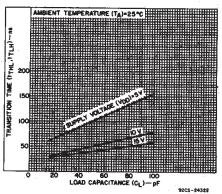


Fig. 6 — Typical transition time as a function of load capacitance.

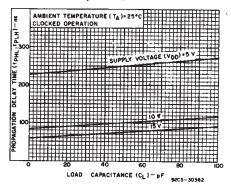


Fig. 7 — Typical propagation delay times as a function of load capacitance (Q output).

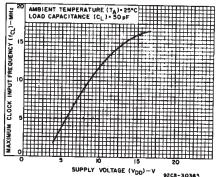


Fig. 8 — Typical maximum clock input frequency as a function of supply voltage.

CD4035B Types

CHARAC- TERISTIC	CON	DITIO	NS	Lim	LIMITS AT INDICATED TEMPERATURE						UNIT
	v _o	VIN	v_{DD}						+25		s
	(V)	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.	
Quiescent	_	0,5	5	5	5	150	150	_	0.04	5	
Device		0,10	10	10	10	300	300	-	0.04	10	μА
Current, IDD Max.	'	0,15	15	20	20	600	600	_	0.04	20	[
DD Max		0,20	20	100	100	3000	3000	-	0.08	100	
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-	
(Sink) Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	-	
IOL Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	-	
Output High	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	_	m/
(Source)	2.5	0,5	5	-2	1.8°	-1.3	-1.15	-1.6	- 3.2	-	
Current,	9.5	0,10	10	1.6	-1.5	-1.1	-0.9	1.3	-2.6	-]
TOH WITH	13.5	0,15	15	-4.2	-4	-2.8	- 2.4	-3.4	-6.8	_	
Output Voltage:	-	0,5	5		0.	.05		_	0	0.05	
Low-Level,	3.1	0,10	10		0	.05			0	0.05	
VOL Max.		0,15	15		0.	05			0	0.05	V
Output		0,5	- 5		4.	95		4.95	5		
Voltage: High-Level,		0,10	10		9	95		9.95	10	.,-	
VOH Min.		0,15	15		14.	95		14.95	15		
leavet Law	0.5,4.5		5			1.5		-	-	1.5	
Input Low Voltage	1,9		10			3			-	3	
V _{IL} Max.	1.5,13.5		15			4			-	4	v
Input High	0.5,4.5		5			3.5		3.5	-	_	
Voltage,	1,9	-	10			7		7	-	_	
V _{IH} Min.	1,5,13.5	- "	15		,	11		11			L
Input Current I _{IN} Max.		0,18	18	±0.1	±0.1	±1	±1	-	±10-5	±0.1	μΔ

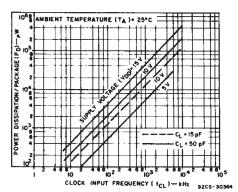


Fig. 9 — Typical dynamic power dissipation as a function of clock input frequency.

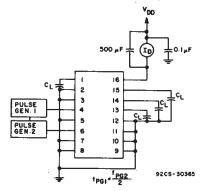


Fig. 10 - Dynamic power dissipation test circuit.

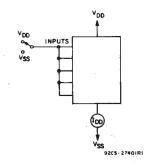


Fig. 11 - Quiescent-device current test circuit.

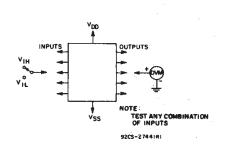


Fig. 12 - Input-voltage test circuit.

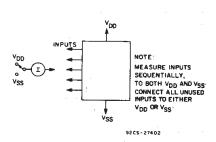


Fig. 13 - Input-current test circuit.

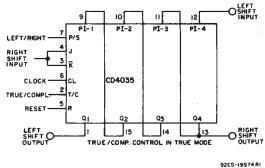
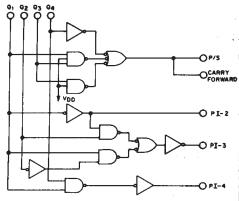


Fig. 14 — Shift left/shift right register.

CD4035B Types



Using Couleur's Technique (BIDEC)^A, a binary number (most significant bit, MSB) first is shifted and processed, such that the BCD equivalent is obtained when the last binary bit is clocked into the register. The CD4035B, with the correct conversion logic, can also be used as a BCD-to-binary converter.

Fig. 15 - BIDEC logic.

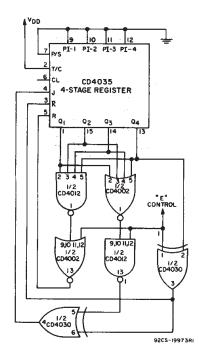


Fig. 16(a) — Double sequence generator.

DYNAMIC ELECTRICAL CHARACTERISTICS

At $T_A = 25^{\circ}C$, Input t_f , $t_f = 20$ ns, $C_L = 50$ pF, $R_L = 200$ k Ω

CHARACTERISTICS		TEST DITIONS				
CHARACTERISTICS		V _{DD} (V)	Min.	Тур.	Max.	UNITS
CLOCKED OPERATION						
Propagation Delay Time:		5		250	500	
tPHL, tPLH		10	-	100	200	ns
		15	-	75	150	Į
Tonnisian Times		5		100	200	
Transition Time: tTHL, tTLH		10	_	50	100	ns
THE TEN		15	<u> </u>	40	80	
		5		100	200	
Minimum Clock Pulse Width, t _W		10		45	90	ns
		15	-	30	60	
Clock Rise or Fall Time, t _f CL, t _f CL*	1	5,10, 15	_	_	15	μs
		5	_	110	220	
Minimum Setup Time: J/K Lines		10	[40	80	ns
J/K Lines		15	_	30	60	
		5	_	70	140	
Parallel-In-Lines		10	_	25	50	กร
		15	-	20	40	
		. 5	2	4	-, 1, 5	
Maximum Clock Frequency, f _{CL}		10	6	12	_ *	MHz
		15	8	16	_	
Input Capacitance, CIN	Any	Input	-	5	7.5	pF
RESET OPERATION						
Propagation Delay Time:		5	_	230	460	
tphL, tpLH		10	_	100	200	ns
		15	-	80	160	
	1	5	_	125	250	
Minimum Reset Pulse Width, tw		10	, – ·	55	110	ns
<u> </u>		15		40	40	

^{*}If more than one unit is cascaded t.CL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

ontrol	E =	O			1		1		
	01	0.2	Q3.	04		0,	02	03	04
	Ä	8	C	. D		, A	В	С	D
	0	0	0	0	15	1	- 11	. 1911	1
1	1 1	0	0	0	114	Õ	1	1.1	1
2	2 0	1	0	0	13	1	0	1	1
Ę	5 1	0	1	0	10	0	1	0	1 .
10	0 (1	0	1	5	1	0	1	0
. 4	0	0	1	0	11	1	1	Ó	1
٤) 1	0	0	1	6	0	1	1	Ó
3	3 1	1	0	0	12	O	0	1	1
6	. 0	1	1	0	9	1	0	0	1
13	3 1	0	1	1	2	0	1	ō	Ó
11	1	1	0	1	4	ō	Ó	ī	ŏ
7	1	1	1	0	8	0	o	Ó	1
14	0	1	1	1	1	1	ō	ă	ò
12	2 0	0	1	1	3	1	1	ō	ō
8	0	0	0	1	1 7	1	1	1	ŏ

Using a control line (E) two different state sequences can be generated. For example, suppose the following two sequences are desired on command (control line E)

Fig. 16(b) — State sequences.

[♠] The basic rule is: If a 4 or less is in a decade, shift with the next clock pulse; if a 5 or greater is in a decade, add 3 and then shift at the next clock pulse. For more information refer to "IRE TRANSACTIONS ON ELECTRONIC COMPUTERS", Dec. 1958, Pages 313—316.

CD4035B Types

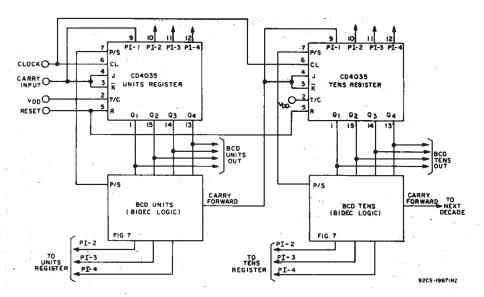
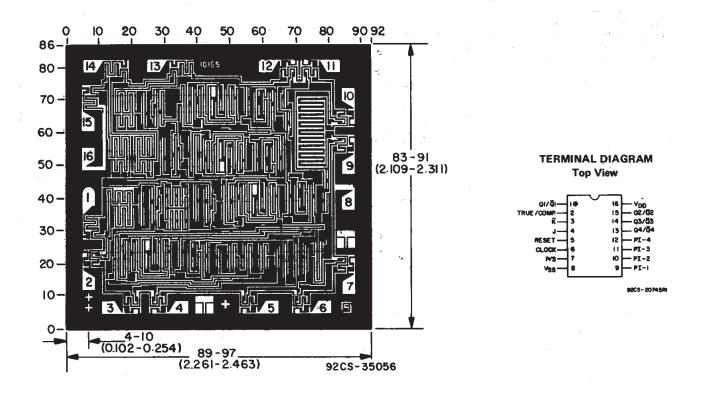


Fig. 17 - Binary-to-BCD converter.



Dimensions and pad layout for CD4035BH.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3}) inch).





25-Sep-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	_	Pins	_	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)		(3)		(4/5)	
8101701EA	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	8101701EA CD4035BF3A	Samples
CD4035BE	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD4035BE	Samples
CD4035BEE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD4035BE	Samples
CD4035BF	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD4035BF	Samples
CD4035BF3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	8101701EA CD4035BF3A	Samples
CD4035BM	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BM96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BM96E4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BM96G4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BME4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BMG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BMT	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BMTE4	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BMTG4	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4035BM	Samples
CD4035BPWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM035B	Samples
CD4035BPWRE4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM035B	Samples
CD4035BPWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM035B	Samples

PACKAGE OPTION ADDENDUM



www.ti.com 25-Sep-2013

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF CD4035B, CD4035B-MIL:

Catalog: CD4035B

• Military: CD4035B-MIL

NOTE: Qualified Version Definitions:





25-Sep-2013

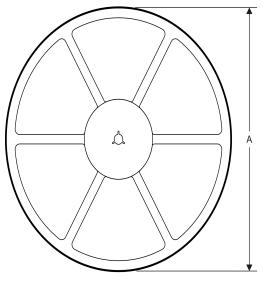
- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

14-Jul-2012 www.ti.com

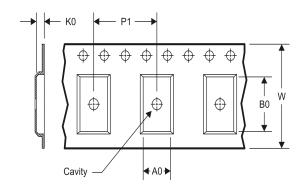
TAPE AND REEL INFORMATION

REEL DIMENSIONS





TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

TAPE AND REEL INFORMATION

*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD4035BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4035BPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Jul-2012



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD4035BM96	SOIC	D	16	2500	333.2	345.9	28.6
CD4035BPWR	TSSOP	PW	16	2000	367.0	367.0	35.0

14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products Applications

Audio www.ti.com/audio Automotive and Transportation www.ti.com/automotive Communications and Telecom **Amplifiers** amplifier.ti.com www.ti.com/communications **Data Converters** dataconverter.ti.com Computers and Peripherals www.ti.com/computers **DLP® Products** www.dlp.com Consumer Electronics www.ti.com/consumer-apps

DSP **Energy and Lighting** dsp.ti.com www.ti.com/energy Clocks and Timers www.ti.com/clocks Industrial www.ti.com/industrial Interface interface.ti.com Medical www.ti.com/medical logic.ti.com Logic Security www.ti.com/security

Power Mgmt power.ti.com Space, Avionics and Defense www.ti.com/space-avionics-defense

Microcontrollers <u>microcontroller.ti.com</u> Video and Imaging <u>www.ti.com/video</u>

RFID www.ti-rfid.com

OMAP Applications Processors www.ti.com/omap TI E2E Community e2e.ti.com

Wireless Connectivity <u>www.ti.com/wirelessconnectivity</u>